
**Fine ceramics (advanced ceramics,
advanced technical ceramics) — Test
method for crystalline quality of
single-crystal thin film (wafer) using
XRD method with parallel X-ray beam**





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CP 401 • Ch. de Blandonnet 8
CH-1214 Vernier, Geneva
Phone: +41 22 749 01 11
Email: copyright@iso.org
Website: www.iso.org

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